ICIM L-EFT

Measuring service IC Immunity Measurement Conductive Coupling Langer EFT Pulses

LANGER EMV-Technik

Short description

The ICIM L-EFT measurement service determines the pulse immunity of ICs using the P202 and P302 pulse generators. During a burst/ESD device test, the generated pulse-shaped disturbances reach the ICs used in the device under test. To test these ICs individually, the pulse generators replicate the attenuated disturbances and enable immunity analysis of each pin/ball of the IC while it is in operation.
The dimensioning of the P202 pulse current generator is based on the mechanisms of interference coupling into electronic assemblies by magnetic fields.
The dimensioning of the P302 pulse voltage generator is based on the mechanisms of interference coupling into electronic assemblies by electric fields.